



#### **N-CHANNEL ENHANCEMENT MODE MOSFET**

#### **Product Summary**

V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> max	I <sub>D</sub> max T <sub>A</sub> = +25°C	
	14mΩ @ V <sub>GS</sub> = 10V	10A	
30V	20mΩ @ V <sub>GS</sub> = 4.5V	8A	

#### **Features and Benefits**

- Low On-Resistance
- Low Input Capacitance
- · Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

### **Description and Applications**

This MOSFET has been designed to minimize the on-state resistance ( $R_{DS(on)}$ ) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

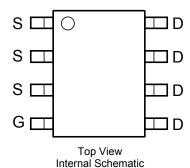
- Backlighting
- Power Management Functions
- DC-DC Converters

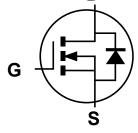
#### **Mechanical Data**

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
   UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram Below
- Weight: 0.072 grams (approximate)









Equivalent circuit

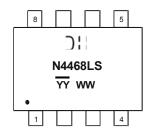
#### **Ordering Information** (Note 4)

Part Number	Case	Packaging
DMN4468LSS-13	SO-8	2500 / Tape & Reel

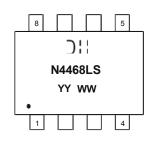
Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- 2. See http://www.diodes.com/quality/lead\_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.

## **Marking Information**



Chengdu A/T Site



Shanghai A/T Site

] i = Manufacturer's Marking
N4468LS = Product Type Marking Code
YYWW = Date Code Marking
YY or YY = Year (ex: 13 = 2013)
WW = Week (01 - 53)

YY = Date Code Marking for SAT (Shanghai Assembly/ Test site)
YY = Date Code Marking for CAT (Chengdu Assembly/ Test site)



# **Maximum Ratings** (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic			Symbol	Value	Unit
Drain-Source Voltage			VDSS	30	V
Gate-Source Voltage			Vgss	±20	V
Continuous Drain Current (Note 5)	Steady State	TA = +25°C TA = +70°C	lD	10 9	Α
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			lрм	50	Α

### **Thermal Characteristics**

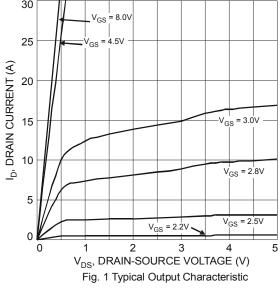
Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 5)	$P_{D}$	1.52	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{ heta JA}$	82	°C/W
Thermal Resistance, Junction to Case (Note 6)	$R_{ heta Jc}$	8.2	°C/W
Operating and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +150	°C

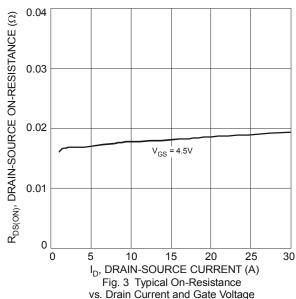
# Electrical Characteristics (@T<sub>A</sub> = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 6)							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30	_	_	<b>V</b>	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current T <sub>J</sub> = +25°C	I <sub>DSS</sub>	_	_	1.0	μΑ	$V_{DS} = 30V, V_{GS} = 0V$	
Gate-Source Leakage	I <sub>GSS</sub>	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 6)							
Gate Threshold Voltage	$V_{GS(th)}$	1.05	_	1.95	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance			11	14	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 11.6A	
Static Drain-Source On-Nesistance	R <sub>DS (ON)</sub>		15	20	11122	$V_{GS} = 4.5V, I_D = 10A$	
Forward Transfer Admittance	Y <sub>fs</sub>	_	8	_	S	$V_{DS} = 5V$ , $I_{D} = 11.6A$	
Diode Forward Voltage	$V_{SD}$	_	0.73	0.95	V	$V_{GS} = 0V, I_{S} = 1A$	
DYNAMIC CHARACTERISTICS (Note 7)						_	
Input Capacitance	C <sub>iss</sub>		867	_	pF	- 101/1/ - 01/	
Output Capacitance	Coss	_	85	_	pF	$V_{DS} = 10V, V_{GS} = 0V,$ - f = 1.0MHz	
Reverse Transfer Capacitance	$C_{rss}$	_	81		рF	71 - 1.01/11/12	
Gate Resistance	$R_{g}$	_	1.39	_	Ω	$V_{DS} = 0V$ , $V_{GS} = 0V$ , $f = 1MHz$	
Total Gate Charge	Qg	_	18.85	_	nC	\\ -40\\\\\ -45\\	
Gate-Source Charge	$Q_{gs}$	_	2.59		nC	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 15V, I <sub>D</sub> =11.6A	
Gate-Drain Charge	$Q_{gd}$	_	6.15	_	nC	ID = 11:0A	
Turn-On Delay Time	$t_{D(on)}$	_	5.46		ns		
Turn-On Rise Time	t <sub>r</sub>	_	14.53	_	ns	V <sub>DD</sub> = 15V, V <sub>GS</sub> = 10V,	
Turn-Off Delay Time	$t_{D(off)}$	_	18.84		ns	$R_L = 1.3\Omega, R_G = 3\Omega, I_D = 1A$	
Turn-Off Fall Time	t <sub>f</sub>	_	6.01	_	ns		

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
- Short duration pulse test used to minimize self-heating effect.
   Guaranteed by design. Not subject to product testing.







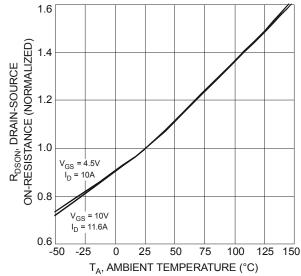
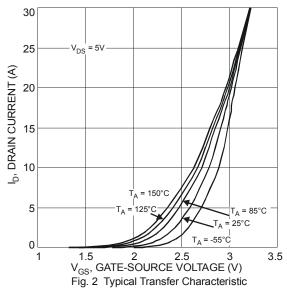


Fig. 5 On-Resistance Variation with Temperature



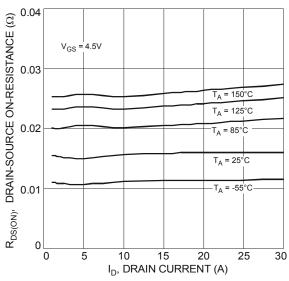


Fig. 4 Typical On-Resistance vs. Drain Current and Temperature

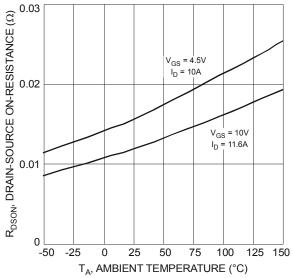


Fig. 6 On-Resistance Variation with Temperature



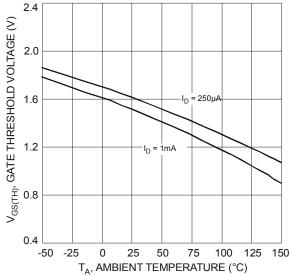
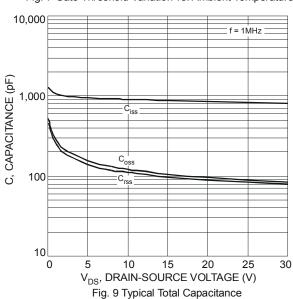
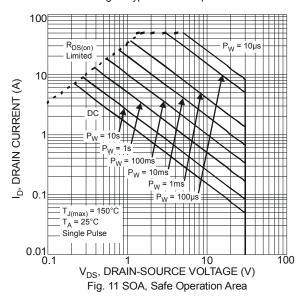
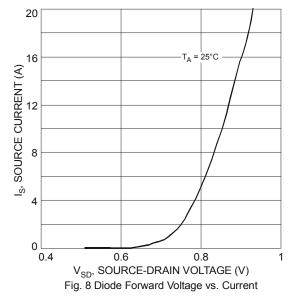


Fig. 7 Gate Threshold Variation vs. Ambient Temperature







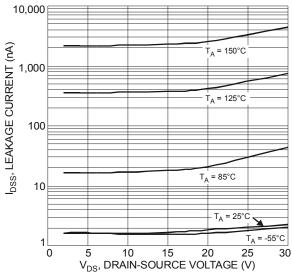
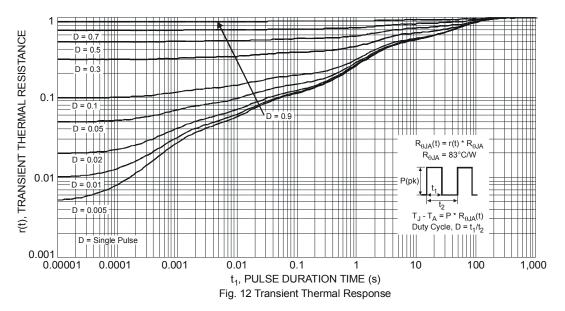


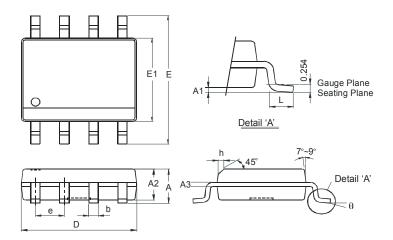
Fig. 10 Typical Leakage Current vs. Drain-Source Voltage





# **Package Outline Dimensions**

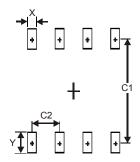
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8				
Dim	Min	Max		
Α	_	1.75		
A1	0.10	0.20		
A2	1.30	1.50		
А3	0.15	0.25		
b	0.3	0.5		
D	4.85	4.95		
Е	5.90	6.10		
E1	3.85	3.95		
е	1.27 Typ			
h		0.35		
L	0.62	0.82		
θ	0°	8°		
All Dimensions in mm				

# **Suggested Pad Layout**

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)
Х	0.60
Y	1.55
C1	5.4
C2	1.27



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